Го	Digi-Key	Issue No.	:	ECJ08082903
		Date of Issue	:	August 29.2008
		Classification	:	■ New □ Changed

PRODUCT SPECIFICATION FOR APPROVAL

Product Description	:	Multilayer Ceramic Chip Capacitors
Product Part Number	:	ECJ2F60J226M (0805 / X6S / 6.3 V / 22 uF)

Customers Part Number	:	
Country of Origin	:	Japan
Applications	:	Consumer Type Electric Equipment

XIf you approve this specification, please fill in and sign the below and return 1 copy to us.

Approval No	:		
Approval Date	:		
Excecuted by	:		
		(signature)	
Title	:		
Dept.	:		

Prepared by : Engineering Section Capacitor Business Unit Phone: +81-123-23-8149 (Direct) Panasonic Electronic Devices Co., Ltd. Fax :+81-123-22-4191 (Direct) 25.Kohata-nishinaka..Uji City, Kyoto, Japan **Contact Person** Title : Phone : +81-774-32-1111(Representative) Authorized by Title : Manager of Engineering If there is a question, please ask the engineering section about it directly

SUBJECT Multilayer Ceramic Chip Capacitors (EIA 0805) PAGE 1 of 1	LASSIFICATION	SPECIFACATION	No. 151	S-ECJ-KBS39E
	SUBJECT	Multilayer Ceramic Chip Capacitors (EIA 0805)	PAGE	1 of 1
High Capacitance (P/N:ECJ2F60J226M) Individual Specification	High Ca	apacitance (P/N:ECJ2F60J226M) Individual Specification	DATE	Aug 28, 2008

1. Scope

This specification applies to High Capacitance Multilayer Ceramic Chip Capacitors (EIA 0805), Temp. Char:X6S, Rated voltage DC6.3 V, Nominal Capacitance 22 μ F.

2. Style and Dimensions



	Table 1
Symbol	Dimensions(mm)
L	2.0 +/- 0.2
W	1.25 +/- 0.20
Т	1.25 +/- 0.20
L1,L2	0.50 +/- 0.25

3. Operating Temperature Range / Storage Temperature Range

Table 2			
	Temperature Characteristics	Operating Temp. Range.	Storage Temperature Range
Class2	X6S	-55 to 105 °C	-55 to 105 °C

4. Individual Specification

Table	3

Part Number	Rated Voltage	Temp. Char.	Nominal Capacitance	Cap. Tolerance
ECJ2F60J226M	DC 6.3 V	X6S	22 μF	+/-20 %

5. Explanation of Part Numbers



6. Temperature Characteristics

Table 4

Temp. Char. Capacitance		Change rate from Temperature	Measurement	Reference	
Code	Temp. Char.	Without voltage application	Temperature Range	Temperature	
6	X6S	+/-22 %	-55 to 105 °C	25 °C	

7. Soldering method

Flow soldering shall not be applied.

Note ;			
	APPROVAL	CHECK	DESIGN
Panasonic Electronic Devices Co., Ltd.	T.Kawamura	T.Shinriki	A.Konishi

CLASSIFICATION	SPECIFICATION	No. 151S-ECJ-KGS39E
SUBJECT	Multilayer Ceramic Chip Capacitors (EIA 0805)	PAGE 1 of 7
High Ca	apacitance (P/N : ECJ2F60J226M) Common Specification	DATE Aug 28, 2008
1- 1.Applicable la (1) Any ozo parts and (2) PBB and (3) All the m Regulati (4) This pro ous Sub (5) This pro Exchang	ws and regulations ne-depleting substances listed in the Montreal Protocol are not used in the manu d materials used in this product. I PBDE are intentionally excluded from materials used in this product. Naterials used in this product are registered materials under the Law Concerning on of Manufacture and Handling of Chemical Substances. duct complies with the RoHS, DIRECTIVE 2002/95/EC on the Restriction of the stances in electrical and electronic equipment. duct is exported with export procedures under export related laws and regulation ge and Foreign Trade Law.	facturing processes for Examination and use of certain Hazard- s such as the Foreign
1- 2.Limitation in This product information safety beca separate sp ∙Aerospa vehicles above.	Applications was designed and manufactured for general-purpose electronic equipment suc & communication equipment. When the following applications, which are requir use the trouble or malfunction of this product may threaten the lives and/or pre ecifications suitable for the application should be exchanged. ace / Aircraft equipment, Warning / Antitheft equipment, Medical equipment, Tran , Trains, Ship and Vessel), Highly public information processing equipment, C	ch as household, office, ed higher reliability and operties, are examined, asport equipment (Motor Others equivalent to the

1-3.Production factory

- (1) Panasonic Electronic Devices Japan Co., Ltd.
- (2) Panasonic Electronic Devices (Tianjin) Co., Ltd. (PEDTJ)

2. Scope

- 2- 1.This specification applies to High Capacitance Multilayer Ceramic Chip Capacitors (P/N : ECJ2F60J226M). If there is a difference between this common specification and any individual specifications, priority shall be given to the individual specifications.
- 2- 2. This product shall be used for general-purpose electronic equipment such as audiovisual, household, office, information & communication equipment.

Unreasonable applications may accelerate performance deterioration or short/open circuits as failure modes affecting the life end.

Adequate safety shall be ensured especially for product design required a high level of safety with the following considerations.

- 1)Previously examine how a single trouble in this product affects the end product.
- 2)Design a protection circuit as Failsafe-design to avoid unsafe system resulting from a single trouble with this product.

Whenever a doubt about safety arises from this product, immediately inform us for technical consultation without fail, please.

- 2- 3. This specification is a part of contract documents pertaining to the trade made by and between your company and Matsushita Electric Industrial Co., Ltd.
- 3. Part Number Code

ECJ	2	F	6	0J	226	Μ
(1)	(2)	(3)	(4)	(5)	(6)	(7)

3- 1.Common Code (1) ECJ : Multilayer Ceramic Chip Capacitors

3-2.Size (2), Packaging Styles (3), Temperature Characteristic (4), Rated Voltage (5), Capacitance Tolerance (7) : Shown in Individual Specification.

	APPROVAL	CHECK	DESIGN
Panasonic Electronic Devices Co., Ltd.	T.Kawamura	T.Shinriki	A.Konishi

CLASSIFICATION	N SPECIFICATION		No. 151S-ECJ-KGS39E			
SUBJECT	Multilayer Ceramic Chip Capacitors (EIA 0805)		PAGE 2 of 7			
High C	High Capacitance (P/N : ECJ2F60J226M) Common Specification					
3- 3.Nominal Ca	pacitance (6)					
The Nomin	hal Capacitance value is expressed in pico farads(pF) and	Symbol (Ex.)	Nominal Cap.			
represent	significant figures and the last digit specifies the number of	105	100000pF $(1 \mu F)$			
zero to follo	ow.	106	1000000pF (10 μF)			
4. Operating Tem Shown in Indiv	nperature Range vidual Specification.					
5. Performance The performar 5- 1.Pretreatmer Before test	nce of the capacitor and its test condition shall be specified in nt t and measurements, the following pretreatment shall be appli	Table 2. ed when neces	ssary.			
5-1-1. Heat Tre The capac perature fo	eatment itors shall be kept in a temperature of 150+0/-10°C for 1 ho or 48±4 hours, before initial measurement.	ur and then sh	all be stored in a room tem-			
5-1-2. Voltage D.C. voltag ture for 48	Treatment ge shall be applied for 1 hour in the specified test condition a +/- 4 hours, before initial measurement.	nd then shall b	e stored in a room tempera-			
6. Test Unless otherw humidity of 45 If results obtai of 60 to 70%.	rise specified, all test and measurements shall be made at a to 75%. ned are doubted a further test should be carried out at a terr	temperature of	¹ 15 to 35°C and at a relative ±2°C and a relative humidity			
7. Structure The structure s	shall be in a monolithic form as shown in Fig. 1.					
	Fig. 1 Table 1		News			
		No.	Name			
/		2 Inne	r electrode			
		3 Subs	strate electrode			
		④ Inter	mediate electrode			
		<u>5</u> Exte	rnal electrode			
Note ;						

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SUBJECT Multilayer Ceramic Chip Capacitors (EIA 0805)

High Capacitance (P/N : ECJ2F60J226M) Common Specification



	Table 2									
No	Content	S	Performance	e			Test M	ethod		
1	Appearance		There shall be no defect the life and use.	s which affect	With a magnifying glass (3 times).			s).		
2	Dimensions		Shown in Individual Spec	cification.	With slid	le calipe	rs and a	microm	neter.	
3	Dielectric Wir ing voltage	thstand-	There shall be no die down or damage.	lectric break-	Test voltage : 250 % of rated voltage Apply a DC voltage of the above val 5 seconds. Charge/discharge current shall 50mA.			tage e value all be	for 1 to within	
4	Insulation Resistance(I.R	ł.)	100/C M Ω min. (C : Nominal Cap. in μ F)		Measuring voltage : Rated voltage Measuring voltage time : 60+/-5s Charge/discharge current shall be v 50mA.			within		
5	Capacitance		Shall be within the specif	fied tolerance.	Meas	suring	Ме	asuring		
6	Dissipation Factor (tan δ)	ctor	0.15 max.		Frequ 120Hz	uency +/-20%	Ve 0.5+/-	oltage 0.2Vrms	6	
					For the class2 Capacitors, perform the treatment in par. 5-1-1. Our Measurement instrument is shown in Table 3.			e heat		
7	Temperature Coefficient	Without Voltage Appli- cation	Temp. Char. X6S : Within +/- 22 %	6	Measure the capacitance at each stage b changing the temperature in the order of step to 4 shown in the table below. Calculate the rate of change regarding the capacitance a stage 3 as the reference.			age by f step 1 ate the ance at it : °C)		
					Temp.			Stage		/
					Char.	1	2	3	4	5
					X6S	25+/-2	-55+/-3	25+/-2	105+/-2	25+/-2
					Meas Frequ 120Hz	suring uency +/-20%	N 0.5+	leasurin Voltage -/-0.2Vrr	g ms	
8	Adhesion	<u> </u>	The terminal electrode sl from peeling or signs of p	hall be free peeling.	Solder the figur direction	he speci re., and h for 10 s	men to apply a seconds	the testi 5N ford	ng jig sh ce in the	nown in e arrow
					Sample			- .		
					Material : Alumina board (95% min.) or glass epoxy board. Thickness : 1.0mm min.				lass	
			[((continue)						
Note	Note ;									

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Multilayer Ceramic Chip Capacitors (EIA 0805) High Capacitance (P/N : ECJ2F60J226M) Common Specification

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	Table 2								
No	No Contents		Contents Performance		Test Method				
9	Bending Strength	Appear- ance Capaci- tance	There s mechan Temp. Char. X6S	shall be no cracks and other ical damage. Change from the value before test. Within +/- 12.5 %	After soldering capacitor on the substrate 1 mm of bending shall be applied for 5 seconds. Bending speed : 1mm/s (shown in Fig. 3)				
10	Vibration Proof	Appear- ance Capaci- tance tan δ	There s mechan Shall be Shall me	hall be no cracks and other ical damage. within the specified tolerance. eet the specified initial value.	Solder the specimen to the testing jig shown in Fig. 2. Apply a variable vibration of 1.5 mm total amplitude in the 10 to 55 to 10Hz vibration frequency range swept in 1 min. in 3 mutually perpendicular directions for 2 hours each, a total of 6 hours.				
11	Resis- tance to Solder Heat	Appear- ance Capaci- tance tan δ I.R. With-stand voltage	There s mechan Temp. Char. X6S Shall me Shall me Shall me down or	hall be no cracks and other ical damage. Change from the value before test. Within +/- 7.5 % eet the specified initial value. eet the specified initial value. hall be no dielectric break- damage.	Solder both method Preconditioning : Heat Temperature (See 5.1.1)/Class2Solder temperature : 270+/-5 °C Dipping period : 3+/-0.5 s Preheat condition :OrderTemp.(°C)Period(s)180 to 1002150 to 200120 to 180Use solder H63A(JIS-Z-3282).For the flux, use rosin (JIS-K-5902) ethanol solution of a concentration of about 25% by weight. Use tweezers for the holder to dip the specimen. Recovery : 48+/-4 hours				
12	12 Solderability		More th of both covered	an 95% of the soldered area terminal electrodes shall be I with fresh solder.	Solder temperature : 230+/-5 °C Dipping period : 4+/-1 s Dip the specimen in solder so that both terminal electrodes are completely submerged. Use solder H63A(JIS-Z-3282). For the flux use rosin (JIS-K-5902) of ethanol solution of a concentration of about 25 % by weight. Use tweezers for the holder to dip the specimen.				
				(continue)					
Note	Note :								

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^{CT} Multilayer Ceramic Chip Capacitors (EIA 0805) High Capacitance (P/N : ECJ2F60J226M) Common Specification

DATE Aug 28, 2008

				Table 2						
No	Conter	nts		Performance	Test Method					
13	Temperature cycle	Appear- ance Capaci- tance	There s mechar Temp. Char.	shall be no cracks and other nical damage. Change from the value before test. Within ±/- 7.5 %	Solder t in Fig. 2 tempera the peri ing this	g jig shown to each nis order for ow. Regard- a perform				
		ton S	Shall m	peet the specified initial value	5 cycles	, periorni				
			Shall m	post the specified initial value.		Temperature	Period			
		With	Thorog	hall be no dielectric break	Step	(°C)	(min.)			
		stand	down o	r damage.	1	Minimum operation temperature +/- 3	30+/-3			
		Voltago			2	Room temperature	3 max.			
					3	Maximum operation temperature +/-5	30+/-3			
					4	Room temperature	3 max.			
					For the treatme Before t specime tempe 48+/	class2 capacitors, perforn nt in par. 5-1-1. the measurement after te en shall be left to stand at rature for the following pe 4-4 h	rm the heat est, the at room period :			
14	Moisture Resistance	Appear- ance	ppear- Ince There shall be no cracks and other mechanical damage.			For the class2 capacitors, perform the heat treatment in par. 5-1-1. Solder the specimen to the testing in shown				
		Capaci- tance	Temp. Char.	Change from the value before test.	in Fig. 2.					
			X6S	Within +/- 20 %	Test t	Test temperature : 40+/-2 °C				
		tan δ	0.25 ma	ax.	Test p	Test period : 500+24/0 h				
		I.R.	10/C M (C : No	Ω min. minal Cap. in $\mu F)$	nin. hal Cap. in μF) Before the measurement after tercimen shall be left to stand at roo ture for the following period : 48+/-4 h					
15	Moisture Resistant	Appear- ance	There s Mechar	shall be no cracks and other nical damage.	For the treatme	class2 capacitors, perform nt in par. 5-1-2.	m the heat			
	Loading	Capaci- tance	Temp. Char.	Change from the value before test.	in Fig. 2	$\frac{1}{2}$				
			X6S	Within +/- 20 %	Relat	ive humidity : 90 to 95 %				
		tan δ	0.25 ma	ax.	Appli	ed voltage : Rated voltage	e			
		I.R.	5/C MΩ (C : No	2 min. minal Cap. in μF)	Char Test	(DC Voltage, ge/discharge current : wit period : 500+24/0 h) hin 50 mA.			
						Before the measurement after test, the spe- cimen shall be left to stand at room tempera- ture for the following period : 48+/-4 h				
				(continue)	48+/	-4 h				

CLASSIFICATION SPECIFICATION							S-ECJ-	-KGS39E	
SUBJECT Multilayer Ceramic Chip Capacitors (EIA 0805)							6	of 7	
	High Capacitance (P/N : ECJ2F60J226M) Common Specification							28, 2008	
Table 2									
No	Conten	its		Performance	Test M	ethod			
16	High Tem- perature Re-	Appear- ance	There s mechar	hall be no cracks and other hical damage.	For the class2 capacit age	ors, per	rform t	he volt-	
	Loading	Capaci- tance	Temp. Char.	Change from the value be- fore test.	Solder the specimen to in Fig. 2.	the test	ing jig :	shown	
		tan δ I.R.	0.25 ma 10/C M (C : No	 ax. Ω min. minal Cap. in μF)	Test temperature : Max. Ra Applied voltage : Rat (DC Charge/discharge cu Test period : 1000+44	re : ix. Rated temp. +/-3°C : Rated voltage (DC Voltage) ge current : within 50 mA. 00+48/0 h			
					Before the measureme cimen shall be left to st ture for the following pe	nt after t and at ro eriod : 48	est, the com ter 3+/-4 h	e spe- mpera-	
Wher moist	uncertainty occ ure resistant loa	curs in the iding, high	weather i temperat	resistance characteristic tests (te ure resistant loading), the same	emperature cycle, moistu tests shall be performed	for the o	ance, capacité	or itself.	
				Table 3					
				Our Standard Measuring Inst	rument				
Mea	asuring Instrume	nt 428	84A Precis	sion LCR Meter (Agilent Technol	ogies)				
Mea	suring Mode	Par	allel Mod	e					
Rec	ommended Measuring	Jig 160)34E Test	Fixture (Agilent Technologies)					
For H We v checł	ligh Cap Type, s vould appreciate king that the fixe	ignal volta e it if you d signal vo	ge may b would co bltage is a	e unable to be applied to depen nfirm whether High Cap Type i applied or not. (For example, ALC	ding on conditions of mea s under the measurable C function is ON, HPA is e	asuring i environ expande	instrum iment (ients. or not by	



CLASSI	FICATION	SPECIFICATIONS		No. 151S-E	CJ-SS018E					
SUBJEC	SUBJECT Multilayer Ceramic Chip Capacitor									
	DATE A	or. 1, 2008								
1. Preca	 Precautions for Use The Multilayer Ceramic Chip Capacitors (hereafter referred to as "Capacitors") may fail in a short circuit mode in an open-circuit mode when subjected to severe conditions of electrical, environmental and/or mechanical stress beyond the specified "Rating and specified "Conditions" in the Specifications, resulting in burn out, flaming or glowing in the worst case. The following "Precautions for Safety" and "Application Notes" shall be taken in your major consideration for use. 									
2. Opera 2- 1.Cir 2-1-1	ating Condit cuit Design . Operating The speci temperatu Temperatu "Storage 1	tions and Circuit Design Temperature and Storage Temperature ified "Operating Temperature Range" in the Specifications is ire rating. Every circuit mounting a Capacitor shall be ope ure Range". The Capacitors mounted on PCB shall be stored femperature Range" in the Specifications.	the absolute rated within t without opera	maximum ar he specified ating within t	nd minimum I "Operating he specified					
 2-1-2. Design of Voltage application The Capacitors shall not be operated exceeding the specified "Rated Voltage" in the Specification. If voltage ratings are exceeded, the Capacitors could result in failure or damage. In case of application of DC and AC voltages to the Capacitors, the designed peak voltage shall be within the specified "Rated Voltage". In case of AC of pulse voltage, the peak voltage shall be within the specified "Rated Voltage". If high frequency voltage or fast rising pulse voltage is applied continuously even within the "Rated Voltage", contact our engineering section before use. Such continuous application affects the life of the Capacitors. 										
2-1-3	. Working C It is recom short circu self-heat c	urrent mended to equip the Capacitors with protection circuits for sat uit with voltages such as secondary voltage, there will be a s or circuit boards might burn out.	fety reasons, a serious risk th	as should the nat the Capa	e Capacitors acitors might					
2-1-4	. Self-Heatir When the temperatu temperatu approval. measured	ng of Capacitors Capacitors self-heat as a result of using AC or pulse v res (25deg.C max.), make sure that the Capacitors' surface terr re plus 20 deg.C (max.), or the maximum operating temperatur Also, the temperature of the Capacitors' surface which vari under the operational mode of devices mounted on by the Capacitors	voltage circuit nperature does re specified in les with circui acitors.	s and opera s not exceed product spe t types used	ate at room the ambient cification for d should be					
2-1-5	. Restriction The Capac (1) Enviro (a) To (b) To (c) Un (2) Under	on Environmental Conditions citors shall not be operated and / or stored under the following e nmental conditions be exposed directly to water or salt water be dew formation der conditions of corrosive gases such as hydrogen sulfide, sulf severe conditions of vibration or impact beyond the specified co	environmental furous acid, ch onditions in the	conditions. Ilorine and ar	nmonia ns					
2-1-6	 2-1-6. DC voltage characteristics The capacitance of Class 2 Capacitors has voltage dependency, contributing to big capacitance fluctuations in high DC voltage application. To secure specified capacitance, the following should be confirmed. (1) That the capacitance fluctuations caused by voltage application are within the capacitance range of a circuit used, or if the capacitance range of a circuit used is broad enough to maintain the Capacitors' functions. (2) DC voltage characteristics demonstrate, even if applied voltage is under the rated voltage, capacitance change rate increases with higher voltage (Capacitance down). Accordingly, when the Capacitors are used for circuits with narrow capacitance allowable range such as time constant circuits, we recommend to apply lower voltage upon due consideration on capacitance aging in addition to the above.									
Note :										
,										
	I	Panasonic Electronic Devices Co., Ltd.	APPROVAL T.Kawamura	CHECK T.Shinriki	DESIGN A.Konishi					

A.Konishi



CLASSIFICATION

SUBJECT

SPECIFICATIONS Multilayer Ceramic Chip Capacitor Common Specification (Precautions for Use)

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No

b

0.25 to 0.30

0.4 to 0.5

0.6 to 0.8

0.8 to 1.0

1.0 to 1.2

1.0 to 1.2

а

0.2 to 0.3

0.4 to 0.5

0.8 to 1.0

0.8 to 1.2

1.8 to 2.2

1.8 to 2.2

2-2-2. Design of Land Pattern

(1) Recommended land dimensions are shown below for proper amount of solder to prevent cracking at the time of excessive stress to the Capacitors due to increased amount of solder.

Component Dimension

Т

0.3

0.5

0.8

0.6 to 1.25

0.6 to 1.6

0.8 to 2.5

W

0.3

0.5

0.8

1.25

1.6

2.5

{ Recommended land dimensions (Ex.) }

[For High Capacitance, General Electronic Equipment, Low ProfileType, 100V·200V series,

Т

0.6

1.0

1.6

2.0

3.2

3.2

Size

(EIA)

0201

0402

0603

0805

1206

1210

630V series, High-Q Capacitors]

Unit in mm c

0.2 to 0.3

0.4 to 0.5

0.6 to 0.8

0.8 to 1.0

1.0 to 1.3

1.8 to 2.3





Solder

resist

						Unit in mm
Size	Compo	onent Di	mension	_	Ŀ	_
(EIA)	L	W	Т	а	D	с
0508	1.25	2.0	0.85	0.5 to 0.7	0.5 to 0.6	1.4 to 1.9
0612	1.6	3.2	0.85	0.8 to 1.0	0.6 to 0.7	2.5 to 3.0

[Array Type]	
--------------	--

<₽



æ

							Unit in mm
Size	Compo	component Dimension			h	0	р
(EIA)	L	W	Т	d	b	C	Г
0805	2.0	1.25	0.95	0.55	0.5	0.2	0.4
4 Array	2.0	1.20	0.65	to 0.75	to 0.6	to 0.3	to 0.6
1206	2.2	16	0.95	0.9	0.7	0.35	0.7
4 Array	3.2	1.0	0.00	to 1.1	to 0.9	to 0.45	to 0.9

2 A	rrav	type	



						L	Init in mm
Size	Component Dimension		а	b	с	Р	
	L	W	Т				
			0.6	0.3	0.45	0.3	0.54
0504	1 27	1.0	0.0	to 0.4	to 0.55	to 0.4	to 0.74
2 Array	1.57	1.0	0.8	0.3	0.4	0.46	0.71
			0.0	to 0.6	to 0.7	to 0.56	to 0.91

(2) The size of lands shall be designed to be equal between the right and left sides. If the amount of solder on the right land is different from that on the left land, the component may be cracked by stress to one side of the component since the side with a larger amount of solder solidifies later at the time of cooling.





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SUBJECT ML	Iltilayer Ceramic Chip C	apacitor		PAGE 4 of 9
Commo	n Specification (Precau	tions for Use))	DATE Apr. 1, 2008
2-2-3. Utilization of Solder R The application of sol PC boards. (1)Solder resis (2)Solder resis · Component · The Capaci · The Capaci See the table below.	esist der resist is effective in prev st shall be utilized to equalize st shall be used to divide the s are arranged closely. tor is mounted near a compo tor is placed near a chassis.	renting solder br the amounts of pattern for the fo nent with lead w	idges and controlling t solder on both sides. blowing cases; ires.	he amount of solder on
	Prohibited Applications an	d Recommende	d Applications	
Mixed mounting with a component with lead wires	Prohibited applica The a cor	tions lead wire of mponent with lead wires Sectional view	Improved applications Solder resist	s by pattern division
Arrangement near chassis	Chassis	ler) Sectional view	Solder resist	Sectional view
Retrofitting of Component with lead wires	Soldering iron	ead wire of Retrofitted component Sectional view	Solder resist	Sectional view
Lateral arrangement	Land	ortion to be excessively soldered		Solder resist
 2-2-4. Component Layout The Capacitors / cor uniform stresses, or to should be done to avoid the PC board. (1) To minimize mech Capacitor layout be 	nponents shall be placed o o position the component ele bid cracking the Capacitors financial stress caused by war below.	n the PC board ctrodes at right rom bending the p or bending of	I such that both elect angles to the grid glove PC board after or duri a PC board, please fol	rodes are subjected to e or bending line. This ng placing/mounting on low the recommended
Warp of Circuit board	Prohibited layout		Recommended layou Lay out t sidew	t he Capacitor vays against the stressing direction
 (2) The following dra mechanical stress position of a PC mounting position (3) The magnitude of the Capacitors wh in the order of p perforation. Also take into Capacitors and th 	wing is for your reference sings near the dividing/break board varies depending on of the Capacitors. If mechanical stress applied the the circuit board is divide bush back < slit < V-groove account the layout of e dividing/breaking method.	nce king the d to Perforation d is e < the	n c c c c c c c c c c c c c c c c c c c	D D O O D O O O O O O O O O O O O O O O
Note ;				

CLASSIFICATION	SPECIFICATIONS		No. 151S-ECJ-SS018E				
SUBJECT N	lultilayer Ceramic Chip Capacitor		PAGE 5 of 9				
Comm	on Specification (Precautions for Use)	DATE Apr. 1, 2008				
2-2-5. Mounting Density an If components are a components are a Solder balls. Eac should be carefully of 3. Precautions for Assembly 3- 1.Storage	 2-2-5. Mounting Density and Spaces If components are arranged in too narrow spaces, the components are affected by Solder bridges and Solder balls. Each space between components should be carefully determined. 3. Precautions for Assembly 3. 1 Storage 						
(1) The Capacitors before conditions of high te	re mounting on PCB shall be stored between	5 - 40°C and 20 - 70%	RH, not under severe				
 (2) If stored in a place hydrogen chloride at In addition, storage and reels. and comp (3) Do not store compo more than 6 months (4) The Capacitors of P capacitance with th dielectric materials. time of shipping. (\$ (5) When the initial cap then subjected to or 	 (1) The objective bolic meaning of the bolic meaning of the bolic bolic bolic bolic treated at 150 meaning of the bolic meaning of the bolic bolic						
 3- 2.Chip Mounting Consideration When mounting the Capacitors/components on a PC board, the capacitor bodies shall be free from excessive impact loads such as mechanical impact or stress in the positioning, pushing force and displacement of vacuu nozzles at the time of mounting. Maintenance and inspections for Chip Mounter must be performed regularly. If the bottom dead center of the vacuum nozzle is too low, the Capacitor is cracked by an excessive force at the time of mounting. The following precautions and recommendations are for your reference in use. Set and adjust the bottom dead center of the vacuum nozzle at the time of mounting to 1 to 3 N in static load. Set the pushing force of the vacuum nozzle at the time of mounting to 1 to 3 N in static load. For double surface mounting, apply a supporting pin on the rear surface of the PC board to suppress the bending of the PC board in order to minimize the impact of the vacuum nozzles. The typical examples all shown in the table below. Adjust the vacuum nozzles so that their bottom dead center at the time of mounting is not too low. (4) The closing dimensions of positioning chucks shall be controlled and the maintenance, checks and replacement of positioning chucks shall be regularly performed to prevent chipping or cracking of the Capacitors caused to mechanical impact at the time of positioning due to worn positioning chucks.							
	Prohibited mounting	Recommende	ed mounting				
Single surface mounting	Crack	Supporting be n pin bene	supporting pin must not ecessarily positioned eath the capacitor.				
Double surface mounting	Separation of solder Crack	Supporting					
Note ;		1					

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3-3.Selection of Soldering Flux

- Soldering flux may seriously affect the performance of the Capacitors. The following shall be confirmed before use. (1) The soldering flux should have a halogen based content of 0.1 wt. % (converted to chlorine) or below. Do not use soldering flux with strong acid.
- (2) When applying water-soluble soldering flux, wash the Capacitors sufficiently because the soldering flux residue on the surface of PC boards may deteriorate the insulation resistance on the Capacitor's surface.

3-4.Soldering

3-4-1. Reflow soldering

The reflow soldering temperature conditions are each temperature curves of Preheating, Temp. rise, Heating, Peak and Gradual cooling. Large temperature difference caused by rapid heat application to the Capacitors may lead to excessive thermal stresses, contributing to the thermal cracks. The Preheating temperature requires controlling with great care so that tombstone phenomenon may be prevented.

	Temperature	Period or Speed
①Preheating	\widehat{D} Preheating 140 to 180 $^{\circ}$ C	
②Temp. rise	Preheating temp. to Peak temp.	2 to 5 °C/s
③Heating	220 °C min.	60 s max.
<pre>④Peak</pre>	260 °C max.	10 s max.
5 Gradual cooling	Peak temp. to 140 $^\circ\!\mathrm{C}$	1 to 4 °C/s

The rapid cooling (forced cooling) during Gradual cooling part should be avoided, because this may cause defects such as the thermal cracks, etc.

When the Capacitors are immersed into a cleaning solvent, confirm that the surface temperature of the devices does not exceed 100°C.

Performing reflow soldering twice under the conditions shown in the figure above [Recommended profile of Reflow soldering (EX)] will not cause any problems. However, pay attention to the possible warp and bending of the PC board.



\langle Allowable temperature difference $\Delta T \rangle$				
Size	Temp.	Tol.		
0201 to 120)6 AT < 1/	50 °C		
0508, 0612, 0	504	50 0		
1210	$\Delta T \leq 13$	30 °C		

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 3-4-2. Hand soldering Hand soldering typically causes significant temperature change, which may induce excessive thermal stresses inside the Capacitors, resulting in the thermal cracks, etc. In order to prevent any defects, the following should be observed; The temperature of the soldering tips should be controlled with special care. The direct contact of soldering tips with the Capacitors and/or terminal electrodes should be avoided. Dismounted Capacitors shall not be reused. 						
(1) Condition (a) Solo	on 1 (with preheating) dering : Dmm or below Thread eutectic solder sin-based and non-activated flux is re heating: capacitors shall be preheated so th oldering iron is 150°C or below. nperature of Iron tip: 300°C max. e required amount of solder shall be r dual Cooling: er soldering, the Capacitors shall be ca	with soldering commended. at the "Tempe nelted in adva poled graduall	flux* in the core. rature Gradient" between nce on the soldering tip.) y at room ambient tempera	the devices and the tip		
Reco	mmended profile of Hand Soldering [I	Ξx.]				
Preh	$\begin{array}{c c} Soldering \\ \hline \\ & & \\$					
(2) Conditi Hand s (a) Solo Cap (b) The tern	 (2) Condition 2 (without preheating) Hand soldering can be performed without preheating, by following the conditions below: (a) Soldering iron tip shall never directly touch the ceramic dielectrics and terminal electrodes of the Capacitors. (b) The lands are sufficiently preheated with a soldering iron tip before sliding the soldering iron tip to the terminal electrodes of the Capacitor for soldering. 					
-	Conditions of Hand so	dering without	preheating Condition			
	Chip size	0201 to 0805	5, 0508, 0504 1206 to 1	210 , 0612		
	Temperature of soldering iron	270 °	<u>C max. 250</u>	°C max.		
	Shape of soldering iron tip		2000 Max.			
	Soldering time with soldering iron 3s max.					
 3- 5.Post Soldering Cleaning 3-5-1. Cleaning solvent Soldering flux residue may remain on the PC board if cleaned with an inappropriate solvent. This may deteriorate the electrical characteristics and reliability of the Capacitors. 3-5-2. Cleaning conditions Inappropriate cleaning conditions such as insufficient cleaning or excessive cleaning may impair the electrical characteristics and reliability of the Capacitors. (1) Insufficient cleaning can lead to: (a) The halogen substance in the residues of the soldering flux to cause the metal of terminal electrodes to corrode. (b) The halogen substance in the residue of the soldering flux on the surface of the Capacitors may change resistance values. 						
Note ;						

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(c) Water-soluble so those of rosin so	oldering flux may have more remarkable te oldering flux.	ndencies of (a) and (b) above compared to			
 (2) Excessive cleaning can lead to: (a) Overuse of ultrasonic cleaning may deteriorate the strength of the terminal electrodes or cause cracking in the solder and/or ceramic bodies of the Capacitors due to vibration of the PC boards. Please follow these conditions for Ultrasonic cleaning:					
3-5-3. Contamination of Cleani Cleaning with contaminate density of liberated haloge	ng solvent ed cleaning solvent may cause the same re n.	sults as insufficient cleaning due to the high			
 3- 6.Inspection Process When mounted PC boards shall not be applied to the P (1) Mounted PC boards sha span 0.5mm max. (2) Confirm that the measur The following figures are 	are inspected with measuring terminal pin IC board or mounted components, to preven all be supported by an adequate number of the pins have the right tip shape, are equal to for your reference to avoid bending the PC	s, abnormal and excess mechanical stress t failure or damage to the devices. supporting pins with bend settings of 90 mm n height and are set in the correct positions. board.			
	Prohibited setting	Recommended setting			
Bending of PC board	Check pin Separated	Check pin Supporting pin			
 3- 7.Protective Coating When the surface of a PC b moisture and dust, it shall used, in order that the reliat that expand or shrink also m 3- 8.Dividing/Breaking of PC Boa (1) Abnormal and excessiv shown below can cause (2) Dividing/Breaking of the speed by using a jig or from mechanical damag (3) Examples of PCB dividir When PC boards are bro the bonding 	 3- 7.Protective Coating When the surface of a PC board on which the Capacitors have been mounted is coated with resin to protect against moisture and dust, it shall be confirmed that the protective coating which is corrosive or chemically active is not used, in order that the reliability of the Capacitors in the actual equipment may not be influenced. Coating materials that expand or shrink also may lead to damage to the Capacitor during the curing process. 3- 8.Dividing/Breaking of PC Boards (1) Abnormal and excessive mechanical stress such as bending or torsion shown below can cause cracking in the Capacitors. (2) Dividing/Breaking of the PC boards shall be done carefully at moderate speed by using a jig or apparatus to prevent the Capacitors on the boards from mechanical damage. (3) Examples of PCB dividing/breaking jigs: 				
the bending Also, planes with no parts mounted on should be used as plane of loading, which generates a compressive stress on the mounted plane, in order to prevent tensile stress induced by the bending, which may cause cracks of the Capacitors or other parts mounted on the PC boards.					
Outline of Jig	Prohibited dividing	Recommended dividing			
PC board PC board PC split	board titing jig	PC board V-groove			
splitting jig					

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3-9.Mech (1) T if N ir (2) V tt V b c c	hanical Impact he Capacitors shall be free from any excessive mechanical impact. he Capacitor body is made of ceramics and may be damaged or cracked dropped. ever use a Capacitor which has been dropped; their quality may be npaired and failure rate increased. //hen handling PC boards with Capacitors mounted on them, do not allow the Capacitors to collide with another PC board. //hen mounted PC boards are handled or stored in a stacked state, impact etween the corner of a PC board and the Capacitor may cause damage or racking and can deteriorate the withstand voltage and insulation esistance of the Capacitor.	Crack Floor Mounted PCB
4. Other		The second se
For spe	tions for Liss shows are from	
	The Technical Report EIAJ RCR-2335 Caution Guide Line for Operation of Fixed I Ceramic Capacitors for Electronic Equipment by Japan Electronics and Information Te ndustries Association (March 2002 issued)	/lultilayer chnology
Please	refer to above technical report for details.	
Note ·		

CLASSFICATION	
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SPECIFICATIONS

1

SUBJECT PAGE Multilayer Ceramic Chip Capacitor (Size:0201 to 1812) **Packaging Specifications**

1. Scope

This specification applies to taped and reeled packing for Multilayer ceramic chip capacitors Size: EIA 0201, EIA 0402, EIA 0603, EIA 0805, EIA 1206, EIA 1210 and EIA 1812.

2. Applicable Standards

- EIAJ (Electric Industries Association of Japan) Standard EIAJ RC-1009B
- JIS (Japanese Industrial Standard) Standard JIS C 0806

3. Packing Specification

3-1.Structure and Dimensions

Paper taping packaging is carried out according the following diagram

- : Shown in Fig. 6. 1) Carrier tape
- 2) Reel : Shown in Fig. 7.
- 3) Packaging : We shall pack suitably in order prevent damage during transportation or storage.

3-2.Packing Quantity

		Carrier-Tape Quanti		Quantity ((pcs./reel)			
Size Thickness of		Thickness of		Toping	ø180mm Reel		ø330mm Reel	
	0126	Capacitor(mm)	Material	Pitch	Packaging Code	Quantity	Packaging Code	Quantity
	0201	0.30 +/- 0.03	Paper Tape (Press Carrier Tape)	2mm	E	15000		
	0402	0.50 +/- 0.05		2mm	E	10000	W	50000
	0603	0.8 +/- 0.1 0.80 +/- 0.15	Paper Tape	4mm	V	4000	Z	10000
		0.6 +/- 0.1	(Funch Carnel Tape)	4mm	V	5000	Z	20000
		0.85 +/- 0.10		4mm	V	4000	Z	10000
	0805	1.25 +/- 0.10 1.25 +/- 0.15 1.25 +/- 0.20	Embossed Tape	4mm	F	3000		
		0.6 +/- 0.1	Paper Tape	4mm	V	5000	Z	20000
	1206	0.85 +/- 0.10	(Punch Carrier Tape)	4mm	V	4000	Z	10000
	1200	1.15 +/- 0.10	Embossed Tape	4mm	F	3000		
		1.6 +/- 0.2		4mm	Y	2000		
	1210	2.0 +/- 0.2		4mm	Y	2000		
	1210	2.5 +/- 0.3		4mm	Y	1000		
	1812	2.5 +/- 0.3		8mm	Y	500		

Explanation of Part Numbers (Example)

3-3.Marking on the Reel

The following items are described in the side of a reel in English at least.

- 1) Part Number
- 2) Quantity
- 3) Lot Number

4) Place of origin

	APPROVAL	CHECK	DESIGN
Panasonic Electronic Devices Co., Ltd.	Y.Sakaguchi	T.Kawamura	A.Konishi





CLASSFICATION SPECIFICATIONS No. 151S-ECJ-SV045E SUBJECT Multilayer Ceramic Chip Capacitor (Size:0201 to 1812) Packaging Specifications PAGE 4 of 6 DATE Sep. 13, 2006 (b) Size 0402 : 2mm pitch for Paper tape (Punch Carrier Tape) Eacd in a hole



Code	Dimension
W	8.0 +/- 0.2
F	3.50 +/- 0.05
E	1.75 +/- 0.10
P ₁	2.00 +/- 0.05
P ₂	2.00 +/- 0.05
P ₀	4.0 +/- 0.1
ϕD_0	1.5 +0.1/0
t ₁	0.7 max.
t ₂	1.0 max.

Unit : mm

(c) Size 0603, 0805 and 1206 : 4mm pitch for Paper tape (Punch Carrier Tape)



Code	Dimension
W	8.0 +/- 0.2
F	3.50 +/- 0.05
Е	1.75 +/- 0.10
P ₁	4.0 +/- 0.1
P ₂	2.00 +/- 0.05
P ₀	4.0 +/- 0.1
ϕD_0	1.5 +0.1/0
t ₁	1.2 max.
t ₂	1.5 max.
	Unit : mm

Size Code	0603	0805	1206
A	1.05 +/- 0.10	1.65 +/- 0.20	2.0 +/- 0.2
В	1.85 +/- 0.10	2.4 +/- 0.2	3.6 +/- 0.2

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SUBJECT Multilayer Ceramic Chip Capacitor (Size:0201 to 1812) Packaging Specifications

(d) Size 0805, 1206 and 1210: 4mm pitch for Embossed tape



-	1	
Code	Dimension	
W	8.0 +/-	0.2
F	3.50 +/-	0.05
E	1.75 +/-	0.10
P ₁	4.0 +/-	0.1
P ₂	2.00 +/- 0.05	
P ₀	4.0 +/- 0.1	
ϕD_0	1.5 +0.1/0	
ϕD_1	1.1+/- 0.1	
t ₁	0.6 max.	
	Size0805	2.5
+.	Size1206	max.
¹ 2	Size1210	3.5
	SIZE 1210	max.

Unit : mm

Size Code	0805	1206	1210
А	1.55 +/- 0.20	1.9 +/- 0.2	2.8 +/- 0.2
В	2.35 +/- 0.20	3.5 +/- 0.2	3.5 +/- 0.2

(e) Size: 1812 : 8mm pitch for Embossed tape



Size Code	1812
А	3.6 +/- 0.3
В	4.9 +/- 0.3

